OCTOBER 1976 - REVISED MARCH 1988

SN54166, SN54LS166A, SN74166, SN74LS166A PARALLEL-LOAD 8-BIT SHIFT REGISTERS

- Synchronous Load
- **Direct Overriding Clear**
- **Parallel to Serial Conversion**

	TYPICAL MAXIMUM	TYPICAL
TYPE	CLOCK FREQUENCY	POWER DISSIPATION
′166	35 MHz	360 mW
'LS166A	35 MHz	100 mW

description

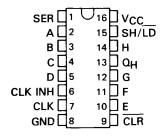
The '166 and 'LS166A 8-bit shift registers are compatible with most other TTL logic families. All '166 and 'LS166A inputs are buffered to lower the drive reauirements to one Series 54/74 or Series 54LS/74LS standard load, respectively. Input clamping diodes minimize switching transients and simplify system design.

These parallel-in or serial-in, serial-out shift registers have a complexity of 77 equivalent gates on a monolithic chip. They feature gated clock inputs and an overriding clear input. The parallel-in or serial-in modes are established by the shift/load input. When high, this input enables the serial data input and couples the eight flip-flops for serial shifting with each clock pulse. When low, the parallel (broadside) data inputs are enabled and synchronous loading occurs on the next clock pulse. During parallel loading, serial data flow is inhibited. Clocking is accomplished on the low-to-high-level edge of the clock pulse through a two-input positive NOR gate permitting one input to be used as a clock-enable or clock-inhibit function. Holding either of the clock inputs high inhibits clocking; holding either low enables the other clock input. This, of course, allows the system clock to be free-running and the register can be stopped on command with the other clock input. The clock inhibit input should be changed to the high level only while the clock input is high. A buffered, direct clear input overrides all other inputs, including the clock, and sets all flip-flops to zero.

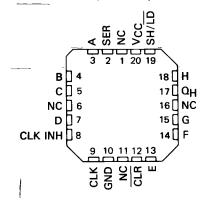
FUNCTION TABLE

		INTE	RNAL	ОПТРИТ				
CLEAR	SHIFT/	CLOCK	OI OOK	SERIAL	PARALLEL	OUT	PUTS	
CLEAR	LOAD	INHIBIT	CLUCK	SERIAL	AH	Q_A Q_B		αH
L	×	×	Х	Х	×	L	7	٦
Н	x	L	L	×	×	QAO	α _{B0}	QH0
н	L	Ł	1	×	a h	а	b	h
н	н	L	1	н	×	н	\mathtt{q}_{An}	q_{Gn}
н	н	L	t	L	×	L	$\mathbf{Q}_{\mathbf{A}\mathbf{n}}$	a_{Gn}
н	x	Н	1	×	Х	Q _{A0}	a_{B0}	σ^{H0}

SN54166, SN54LS166A . . . J OR W PACKAGE SN74166 . . . N PACKAGE SN74LS166A . . . D OR N PACKAGE (TOP VIEW)

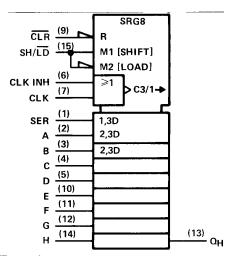


SN54LS166A . . . FK PACKAGE (TOP VIEW)



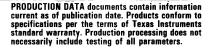
NC - No internal connection

logic symbol †

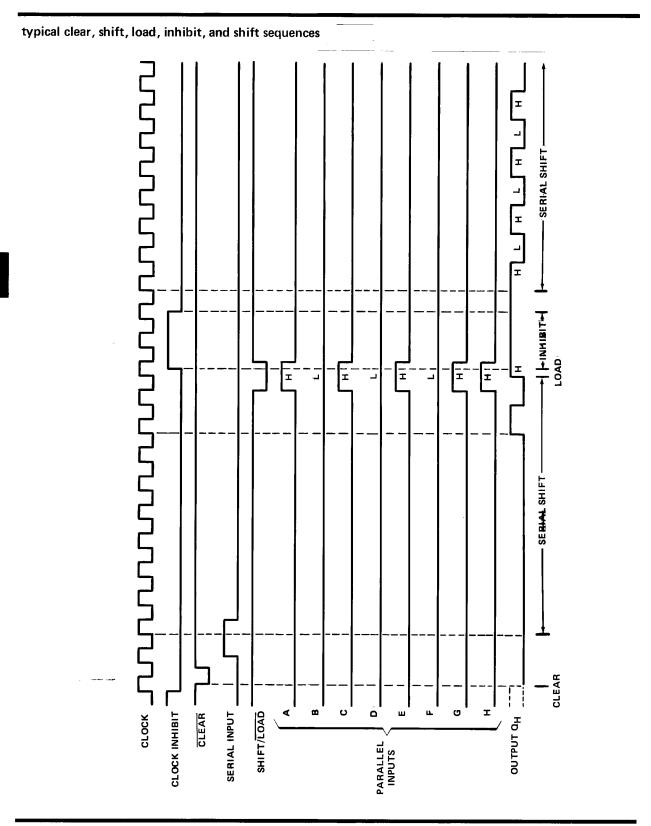


[†]This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

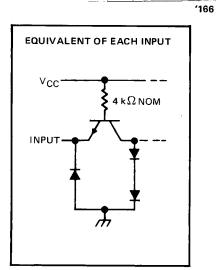


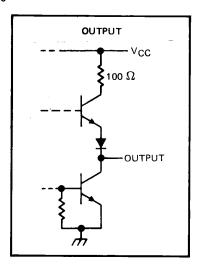




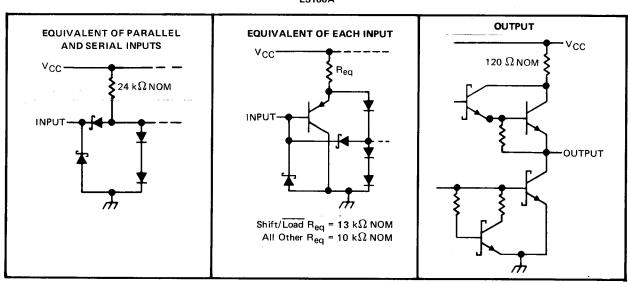


schematics of inputs and outputs



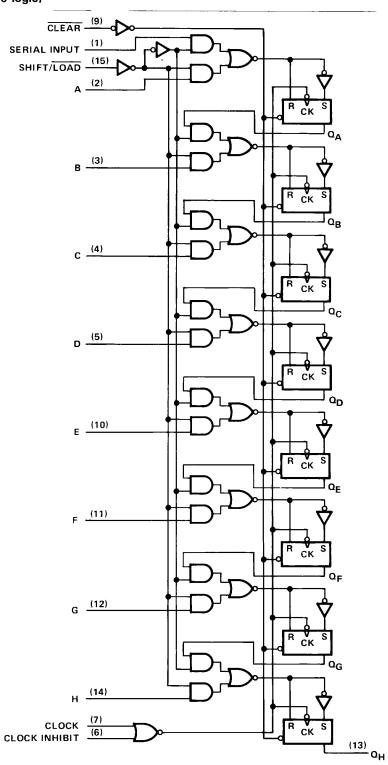


'LS166A



SN54166, SN54LS166A, SN74166, SN74LS166A PARALLEL-LOAD 8-BIT SHIFT REGISTERS

logic diagram (positive logic)



Pin numbers shown are for D, J, N, and W packages.



SN54166, SN74166 PARALLEL-LOAD 8-BIT SHIFT REGISTERS

olute maximum ratings over operating free-air temperature range (unless otherwise noted)	
Supply voltage, V _{CC} (see Note 1)	٧
Input voltage	V
Operating free-air temperature range: SN54166 (see Note 2)	С
SN74166	
Storage temperature range	С
ommended operating conditions	

	,	SN54166			LINIT		
	MIN	NOM	MAX	MIN	NOM	MAX	TINU
Supply voltage, V _{CC}	4.5	5	5.5	4.75	5	5.25	V
High-level output current, IOH			-800			-800	μΑ
Low-level output current, IOL			16			16	mA
Clock frequency, fclock	0		25	0		25	MHz
Width of clock or clear pulse, tw (see Figure 1)	20			20			ns
Mode-control setup time, t _{su}	30			30			ns
Data setup time, t _{SU} (see Figure 1)	20			20			ns
Hold time at any input, th (see Figure 1)	0			0			ns
Operating free-air temperature, TA (see Note 2)	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	DADAMETED	TEST CONDITIONS†	AUDITIONS!		6	SN74166			
	PARAMETER	TEST CONDITIONS	MIN	TYP‡	MAX	MIN	TYP‡	MAX	UNIT
VIH	High-level input voltage		2			2			٧
VIL	Low-level input voltage				8.0			0.8	V
VIĶ	Input clamp voltage	V _{CC} = MIN, I _I = -12 mA			-1.5			-1.5	V
V _{OH}	High-level output voltage	V _{CC} = MIN, V _{IH} = 2 V, V _{IL} = 0.8 V, I _{OH} = -800 μA	2.4	3.4		2.4	3.4		V
VOL	Low-level output voltage	V _{CC} = MIN, V _{IH} = 2 V, V _{IL} = 0.8 V, I _{OL} = 16 mA		0.2	0.4		0.2	0.4	٧
Ч	Input current at maximum input voltage	V _{CC} = MAX, V _I = 5.5 V			1	-		1	mA
ЧН	High-level input current	V _{CC} = MAX, V _I = 2.4 V			40			40	μА
ΗL	Low-level input current	V _{CC} = MAX, V _I = 0.4 V			-1.6			-1.6	mA
los	Short-circuit output current§	V _{CC} = MAX	-20		-57	-18		-57	mA
Icc	Supply current	V _{CC} = MAX, See Note 3		90	127		90	127	mA

[†]For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

- NOTES: 1. Voltage values are with respect to network ground terminal.
 - 2. An SN54166 in the W package operating at free-air temperatures above 113° C requires a heat-sink that provides a thermal resistance from case to free air, $R_{\theta CA}$, of not more than 48° C/W.
 - 3. With all outputs open, 4.5 V applied to the serial input, all other inputs except the clock grounded, I_{CC} is measured after a momentary ground, then 4.5 V, is applied to the clock.

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ} \text{ C}$

PARAMETER		TEST CONDITIONS		TYP	MAX	UNIT
f _{max}	Maximum clock frequency		25	35		MHz
	Propagation delay time, high-to-	w-level output from clear $C_L = 15 pF$, $R_L = 400 \Omega$, opagation delay time, high-tow-level output from clock See Figure 1			25	
^t PHL	low-level output from clear			23	35	ns
	Propagation delay time, high-to-			20		
tPHL	low-level output from clock			20	30	ns
	Propagation delay time, low-to-			17	20	
tPLH	high-level output from clock			17	26	ns



 $^{^{\}ddagger}_{c}$ All typical values are at $V_{CC} = 5 \text{ V}$, $T_{A} = 25^{\circ}\text{C}$.

 $[\]S$ Not more than one output should be shorted at a time.

SN54LS166A, SN74LS166A PARALLEL-LOAD 8-BIT SHIFT REGISTERS

absolute maximum ratings over operat		
Supply voltage, VCC (see Note 1)		 7 V
Input voltage		 7 V
Operating free-air temperature range:		
	SN74LS166A	 0°C to 70°C
Storage temperature range		 65° C to 150° C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

		SI	N54LS1	66A	SN74LS166A				
		MIN	TYP	MAX	MIN	TYP	MAX	רומט	
VCC	Supply voltage	4.5	5	5.5	4.75	5	5.25	V	
v_{IH}	High-level input voltage	2			2			V	
VIL	Low-level input voltage			0.7			0.8	V	
Юн	High-level output current			- 0.4			- 0.4	mA	
lor	Low-level output current			4			8	mA	
f _{clock}	Clock frequency	0	_	25	0		25	MHz	
t _w	Width of clear pulse (See Figure 1)	20			20			ns	
t _w	Width of clock pulse (See Figure 1)	25			25			-	
t _{su}	Mode-control setup time	30			30			ns	
tsu	Data setup time (See Figure 1)	20			20			ns	
th	Hold time at any input (See Figure 1 and Note 4)	0		•	0			ns	
TA	Operating free air temperature	– 55		125	0		70	°c	

NOTE 4: The hold time limit of 0 ns applies only if the rise time is less than or equal to 10 ns.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS †		81	SN	UNIT				
TANAMETER			MIN	TYP‡	MAX	MIN	TYP‡	MAX	UNIT
V _{IK}	V _{CC} = MIN, I _I = − 18 mA				- 1.5			– 1.5	V
Voн	$V_{CC} = MIN, V_{IH} = 2 V, V_{IOH} = -0.4 \text{ mA}$	L=MAX,	2.5	3.4		2.7	3.4		V
	V _{CC} = MIN, V _{IH} = 2 V, I _O	L = 4 mA		0.25	0.4		0.25	0.4	— ,
VOL	VIL = MAX	L≈8mA					0.35	0.5	†
. Ij	V _{CC} = MAX, V _I = 7 V				0.1			0.1	mA
ЧН .	V _{CC} = MAX, V _I = 2.7 V				20			20	μΑ
IΙL	V _{CC} = MAX, V _I = 0.4 V				- 0.4			- 0.4	mA
los§	V _{CC} = MAX		- 20		– 100	20		- 100	mA
Icc	V _{CC} = MAX, See Note 5			20	32		20	32	mA

†For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

 \pm All typical values are at $V_{CC} = 5 \, V$, $T_A = 25 \, ^{o}C$.

§Not more than one output should be shorted at a time, and duration for short-circuit should not exceed one second.

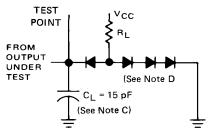
NOTE 5: With all outputs open, 4.5 V applied to the serial input and all other inputs except the clock grounded, ICC is measured after a momentary ground, than 4.5 V, is applied to clock.

switching characteristics, V_{CC} = 5 V, T_A = 25°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
fmax	Maximum clock frequency		25	35		MHz
	Propagation delay time, high-to-		-			
tPHL.	low-level output from clear	0 45 5 0 010		19	30	ns
•=	Propagation delay time, high-to-	$C_L = 15 \mathrm{pF}, R_L = 2 \mathrm{k}\Omega,$	-	- 44		
tPHL	low-level output from clock	See Figure 1	,	14	25	ns
to	Propagation delay time, low-to-	-	_			
tPLH	high-level output from clock		5	11	20	ns



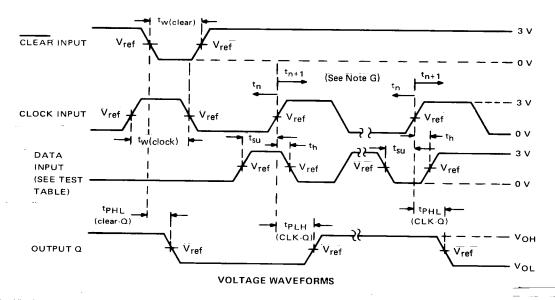
PARAMETER MEASUREMENT INFORMATION



LOAD FOR OUTPUT UNDER TEST

TEST TABLE FOR SYNCHRONOUS INPUTS

DATA INPUT FOR TEST	SHIFT/LOAD	OUTPUT TESTED (SEE NOTE F)
н	0 V	Q _H at t _{n+1}
Serial Input	4.5 V	Q _H at t _{n+8}



NOTE: A. All pulse generators have the following characteristics: $Z_{OUt} \approx 50Q$; for '166, $t_r \leqslant 7$ ns. and $t_f \leqslant 7$ ns; for 'LS166A, $t_r \leqslant 15$ ns and $t_f \leqslant 6$ ns.

- B. The clock pulse has the following characteristics: t_{W(clock)} ≤ 20 ns and PRR = 1 MHz. The clear pulse has the following characteristics: t_{W(clear)} ≤ 20 ns and t_{hold} = 0 ns. When testing f_{max}, vary the clock PRR.
- C. C_L includes probe and jig capacitance.
- D. All diodes are 1N3064, 1N916, or equivalent.
- E. A clear pulse is applied prior to each test.
- F. Propagation delay times (t_{PLH}) and t_{PHL} are measured at t_{n+1} . Proper shifting of data is verified at t_{n+8} with a functional test.
- G. t_n = bit time before clocking transition
 - t_{n+1} = bit time after one clocking transition
 - t_{n+8} = bit time after eight clocking transitions
- H. For '166 $V_{ref} = 1.5 V$; for 'LS166A $V_{ref} = 1.3 V$.

FIGURE 1

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